Applicant(s)/Patent Under Application/Control No. Reexamination 10/667,001 BATES ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2191 Anil Khatri

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*		US-5,933,639	08-1999	Meier et al.	717/129
*	<u> </u>	US-7,107,578	09-2006	Alpern, David M.	717/124
*	В	US-6,263,489	07-2001	Olsen et al.	717/129
*	<u> </u>	US-5,764,989	06-1998	Gustafsson et al.	717/129
*	<u>D</u>	US-6,895,577	05-2005	Noble et al.	717/126
*	E	US-6,721,941	04-2004	Morshed et al.	. 717/127
*	F	US-6,817,010	11-2004	Aizenbud-Reshef et al.	717/127
*	G	US-7,133,820	11-2006	Pennello et al.	703/22
*	Н .	US-6,681,384	01-2004	Bates et al.	717/129
	 	US-	+		
	J	US-	 		
	K	US-	<u> </u>		
	L	US-	 		
	M	100-		FOREIGN PATENT DOCUMENTS	

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

		NON-PATENT DOCUMENTS		
*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Chem et al, "Debugging with control flow breakpoints", ACM AOSD, pp 96-106, 2007		
	٧	Koch et al, "Breakpoints and breakpoint detection in source level emulation", IEEE ISSS, pp 26-31, 1996		
	w	Iqbal et al, "Undersanding and developing models for detecting and differentiating breakpoints during interactive tasks" ACM CHI, pp 697-706, 2007		
	x	Wahbe et al, "Practical data breakpoints: design and implementations", ACM SIGPLAN PLDI, pp 1-12, 1993		

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Patent and Trademer Coffice PTO-892 (Rev. 01-2001)

Notice of References Cited

Part of Paper No. 20070519